transphorm

TPH3206PSB Discontinued

650V GaN FET in TO-220 (source tab)

Description

The TPH3206PSB 650V, $150m\Omega$ Gallium Nitride (GaN) FET is a normally-off device. It combines state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

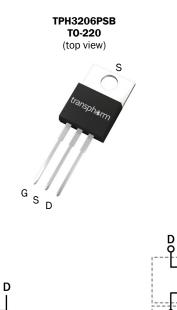
Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

Related Literature

- AN0009: Recommended External Circuitry for GaN FETs
- AN0003: Printed Circuit Board Layout and Probing
- AN0010: Paralleling GaN FETs

Ordering Information

	Part Number	Package	Package Configuration
TF	PH3206PSB	3 lead T0-220	Source



Features

- JEDEC qualified GaN technology
 Dynamic R_{DS(on)eff} production tested
- Bynamic RDS(on)eff production
 Robust design, defined by
- Intrinsic lifetime tests
- Wide gate safety margin
- Transient over-voltage capability
- Very low Q_{RR}
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

Benefits

- Enables AC-DC bridgeless totem-pole PFC designs
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- Achieves increased efficiency in both hard- and softswitched circuits
- · Easy to drive with commonly-used gate drivers
- GSD pin layout improves high speed design

Applications

- Datacom
- Broad industrial
- PV inverter
- Servo motor

Key Specifications

V _{DSS} (V)	650		
V _{(TR)DSS} (V)	800		
$R_{DS(on)eff}(m\Omega)$ max*	180		
Q _{RR} (nC) typ	52		
Q _G (nC) typ	6.2		

 * Dynamic on-resistance; see Figures 19 and 20

Common Topology Power Recommendations				
CCM bridgeless totem-pole*	1519W max			
Hard-switched inverter**	1717W max			

Conditions: F_{SW} =45kHz; T_J=115°C; T_{HEATSINK}=90°C; insulator between device and heatsink (6 mil Sil-Pad® K-10); power de-rates at lower voltages with constant current

* VIN=230VAC; VOUT=390VDC

DS

Cascode Device Structure

** VIN=380VDC; VOUT=240VAC

Cascode Schematic Symbol

Absolute Maximum Ratings (Tc=25°C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit		
V _{DSS}	Drain to source voltage $(T_J = -\xi$	55°C to 150°C)	650			
V _{(TR)DSS}	Transient drain to source voltage a		Transient drain to source voltage ^a		800	V
V _{GSS}	Gate to source voltage		±18			
PD	Maximum power dissipation @	₽Tc=25°C	81	W		
	Continuous drain current @Tc=	=25°C ^b	16	А		
ID	Continuous drain current @Tc=	=100°C b	10	А		
I _{DM}	I _{DM} Pulsed drain current (pulse width: 10μs)		60	А		
(di/dt) _{RDMC}	(di/dt) _{RDMC} Reverse diode di/dt, repetitive °		1200	A/µs		
(di/dt) _{RDMT}	Reverse diode di/dt, transient d		2400	A/µs		
Tc	Operating temperature	Case	-55 to +150	°C		
٦J	TJ Operating temperature		-55 to +150	°C		
Ts	s Storage temperature		-55 to +150	°C		
T _{SOLD}	Soldering peak temperature ^e		260	°C		

Notes:

a. In off-state, spike duty cycle D<0.01, spike duration <1µs

b. For increased stability at high current operation, see Circuit Implementation on page 3

c. Continuous switching operation

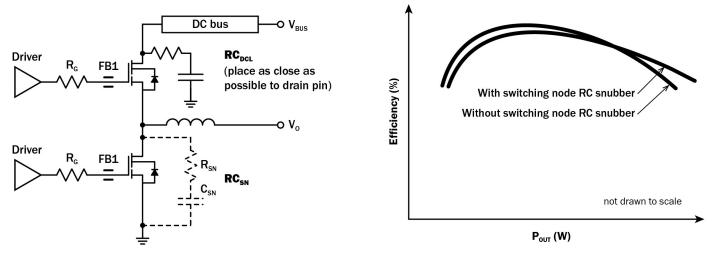
d. \leq 300 pulses per second for a total duration \leq 20 minutes

e. For 10 sec., 1.6mm from the case

Thermal Resistance

Symbol	Parameter	Typical	Unit
R _{0JC}	Junction-to-case	1.55	°C/W
R _{OJA}	Junction-to-ambient	62	°C/W

Circuit Implementation



Simplified Half-bridge Schematic

Efficiency vs Output Power

Recommended gate drive: (0V, 8-10V) with $R_{G(tot)} = 25\Omega$, where $R_{G(tot)} = R_{G} + R_{DRIVER}$

Gate Ferrite Bead (FB1)	Required DC Link RC Snubber (RC_{DCL}) ^a	Recommended Switching Node RC Snubber (RC _{SN}) ^{b, c}
MMZ1608Q121BTA00	10nF + 8Ω	22pF + 15Ω

Notes:

a. RC_{DCL} should be placed as close as possible to the drain pin

b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of I_{RDMC1} or I_{RDMC2}; see page 5 for I_{RDMC1} and I_{RDMC2})

c. IRDM values can be increased by increasing RG and CSN

TPH3206PSB (Discontinued)

Electrical Parameters (T_=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Forward Device Characteristics							
$V_{(BL)DSS}$	Drain-source voltage	650	_	-	V	V _{GS} =OV	
$V_{\text{GS}(\text{th})}$	Gate threshold voltage	1.65	2.1	2.6	V	V _{DS} =V _{GS} , I _D =500µA	
D		-	150	180	mΩ	V _{GS} =8V, I _D =10A	
$R_{DS(on)eff}$	Drain-source on-resistance ^a	_	308	_		V _{GS} =8V, I _D =10A, T _J =150°C	
I	Drain to course lookage ourrent	-	2.5	30		V _{DS} =650V, V _{GS} =0V	
I _{DSS}	Drain-to-source leakage current	_	8	_	μA	V _{DS} =650V, V _{GS} =0V, T _J =150°C	
1	Gate-to-source forward leakage current	-	_	100	nA	V _{GS} =18V	
I _{GSS}	Gate-to-source reverse leakage current	-	_	-100		V _{GS} =-18V	
CISS	Input capacitance	-	720	-		V _{GS} =0V, V _{DS} =480V, <i>f</i> =1MHz	
Coss	Output capacitance	-	46	-	pF		
C _{RSS}	Reverse transfer capacitance	-	5.5	-			
$C_{O(er)}$	Output capacitance, energy related b	-	65	-	pF	V_{GS} =0V, V_{DS} =0V to 480V	
C _{O(tr)}	Output capacitance, time related ^c	-	106	-	рг		
Q_{G}	Total gate charge	-	6.2	-			
Q _{GS}	Gate-source charge	-	2.1	-	nC	V_{DS} =100V, V_{GS} =0V to 4.5V, I_D=10A	
Q_{GD}	Gate-drain charge	-	2.2	-			
Qoss	Output charge	_	44.4	_	nC	V_{GS} =0V, V_{DS} =0V to 400V	
t _{D(on)}	Turn-on delay	_	6	-			
t _R	Rise time	-	4.5	_	ns	V_{DS} =480V, V_{GS} =0V to 10V,	
$t_{\text{D(off)}}$	Turn-off delay	_	9.7	-	115	I_D =10A, R_G =22 Ω	
t _F	Fall time	_	4	_			

Notes:

a. Dynamic on-resistance; see Figures 19 and 20 for test circuit and conditions b. Equivalent capacitance to give same stored energy as V_{DS} rises from OV to 400V

c. Equivalent capacitance to give same charging time as V_{DS} rises from OV to 400V

TPH3206PSB (Discontinued)

Electrical Parameters (T_=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
Reverse Device Characteristics						
Is	Reverse current	_	_	10	A	V _{GS} =0V, T _C =100°C, ≤25% duty cycle
		_	2.4	-		V _{GS} =0V, I _S =10A
V _{SD}	Reverse voltage ^a	_	3.7	-	v	V _{GS} =0V, I _S =10A, T _J =150°C
		_	1.7	_	-	V _{GS} =0V, I _S =5A
t _{RR}	Reverse recovery time	_	17	-	ns	I _S =11A, V _{DD} =400V,
Q _{RR}	Reverse recovery charge	_	52	-	nC	di/dt=2000A/µs
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive b	_	-	1200	A/µs	
IRDMC1	Reverse diode switching current, repeti- tive (dc) ^{c, e}	_	_	11	A	Circuit implementation and parameters on page 3
I _{RDMC2}	Reverse diode switching current, repeti- tive (ac) ^{c, e}	_	_	14	A	Circuit implementation and parameters on page 3
(di/dt) _{RDMT}	Reverse diode di/dt, transient d	_	_	2400	A∕µs	
I _{RDMT}	Reverse diode switching current, transient ^{d,e}	_	-	18	A	Circuit implementation and parameters on page 3

Notes:

a. Includes dynamic R_{DS(on)} effect

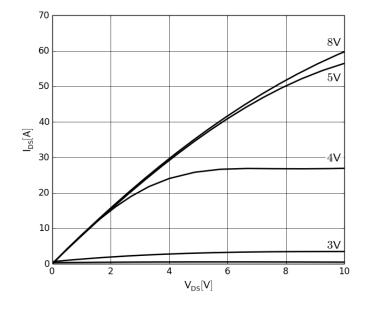
b. Continuous switching operation

c. Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency

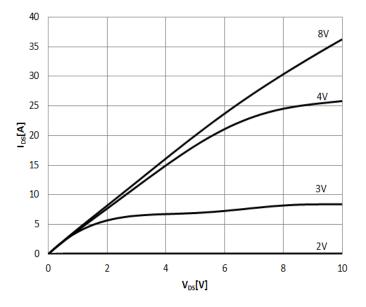
d. \leq 300 pulses per second for a total duration \leq 20 minutes

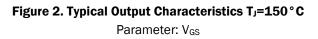
e. $~~I_{RDM}$ values can be increased by increasing R_{G} and C_{SN} on page 3

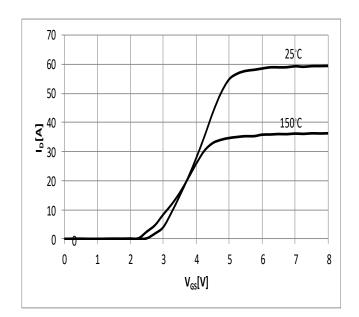
Typical Characteristics (Tc=25 $^{\circ}$ C unless otherwise stated)

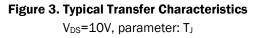


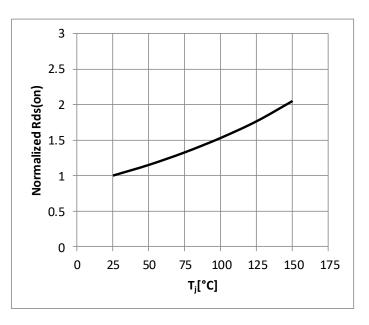


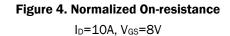












Typical Characteristics (Tc=25 °C unless otherwise stated)

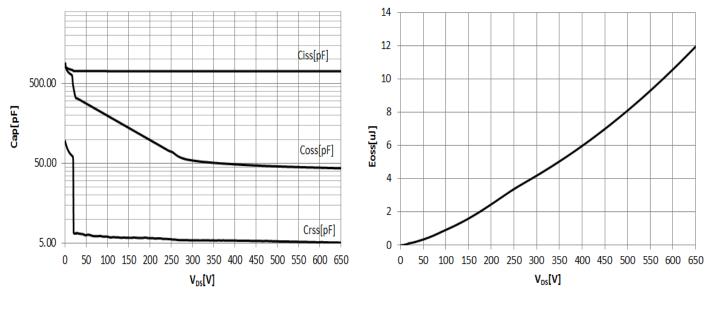
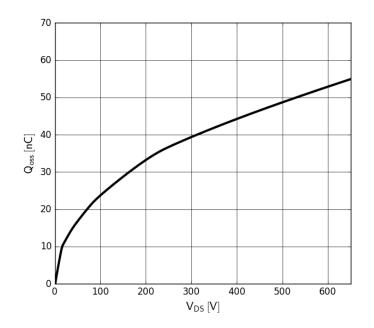
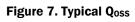


Figure 5. Typical Capacitance

 V_{GS} =0V, f=1MHz

Figure 6. Typical Coss Stored Energy





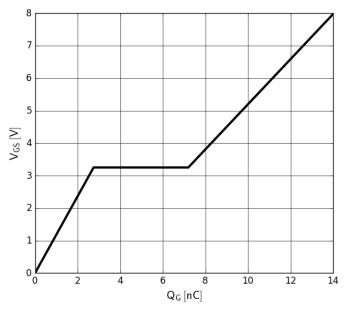
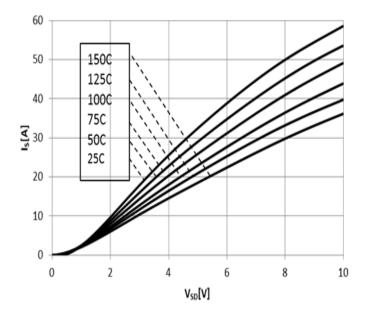
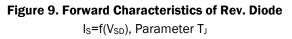


Figure 8. Typical Gate Charge I_{DS}=10A, V_{DS}=400V

Typical Characteristics (Tc=25 °C unless otherwise stated)





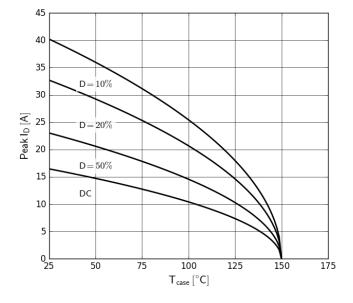


Figure 10. Current Derating Pulse width = 100µs

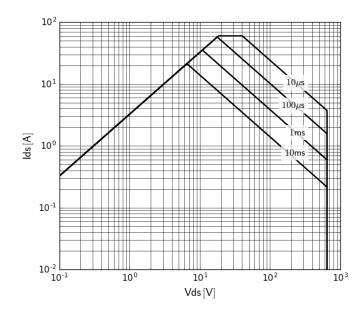
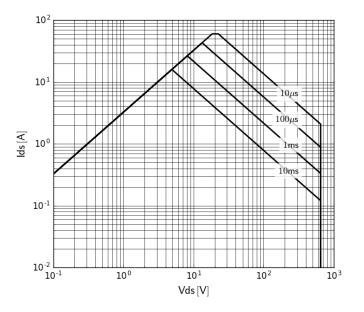
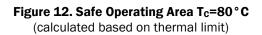


Figure 11. Safe Operating Area Tc=25°C (calculated based on thermal limit)





100

80

60

40

20

0 L 0

 $\mathsf{P}_{\mathrm{tot}}\left[\mathsf{W}\right]$

Typical Characteristics (Tc=25 °C unless otherwise stated)

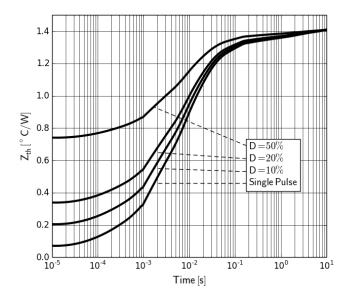




Figure 14. Power Dissipation

50

100

 $\mathsf{T}_{\mathsf{case}}\left[^{\circ}\mathsf{C}\right]$

150

200

Test Circuits and Waveforms

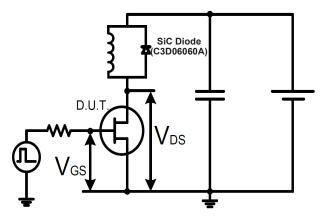


Figure 15. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

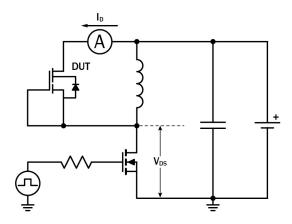


Figure 17. Diode Characteristics Test Circuit

 \mathbf{R}_{SNS}

DUT

VDS

Ŧ

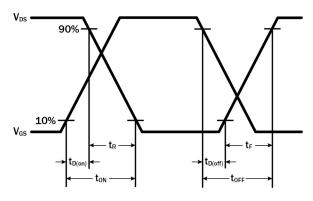


Figure 16. Switching Time Waveform

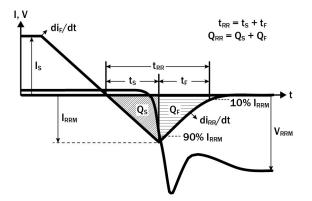
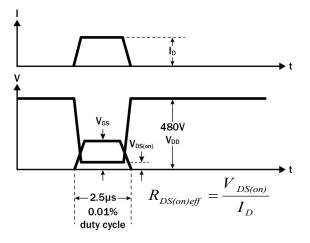
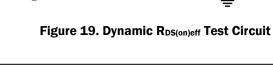


Figure 18. Diode Recovery Waveform







Vgs

Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power</u> <u>Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

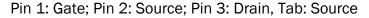
GaN Design Resources

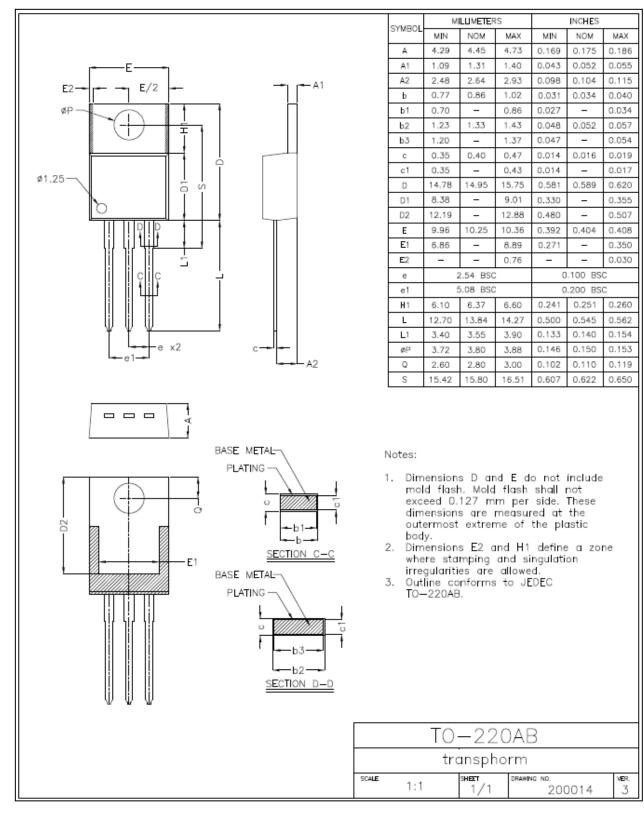
The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Reference designs
- Evaluation kits
- Application notes
- Design guides
- Simulation models
- Technical papers and presentations

Mechanical

3 Lead TO-220 (PS) Package





Mar. 7, 2017 tph3206p.3

TPH3206PSB (Discontinued)

Revision History

Version	Date	Change(s)	
0	11/7/2016	B version integrates bleed resistor	
1	4/19/2017	Updated package drawing	
2	11/2/2017	 Updated Figures 11 & 12 (pg 7), effective on-resistance symbol to R_{DS(on)eff} to adhere to new JEDEC standards; Added common topology max power recommendations (pg 1), switching current values (pg 2), Circuit Implementation (pg 3), Q_{OSS} value (pg 4), Figures 7 & 8 (pg 6) 	
3	3/7/2021	Product discontinued	

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